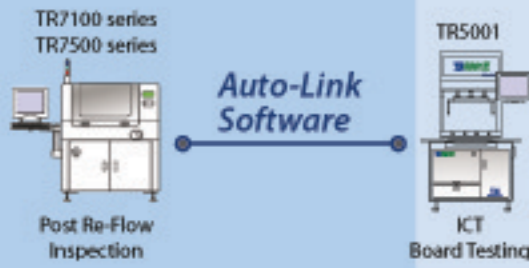


SOFTWARE AND NETWORK

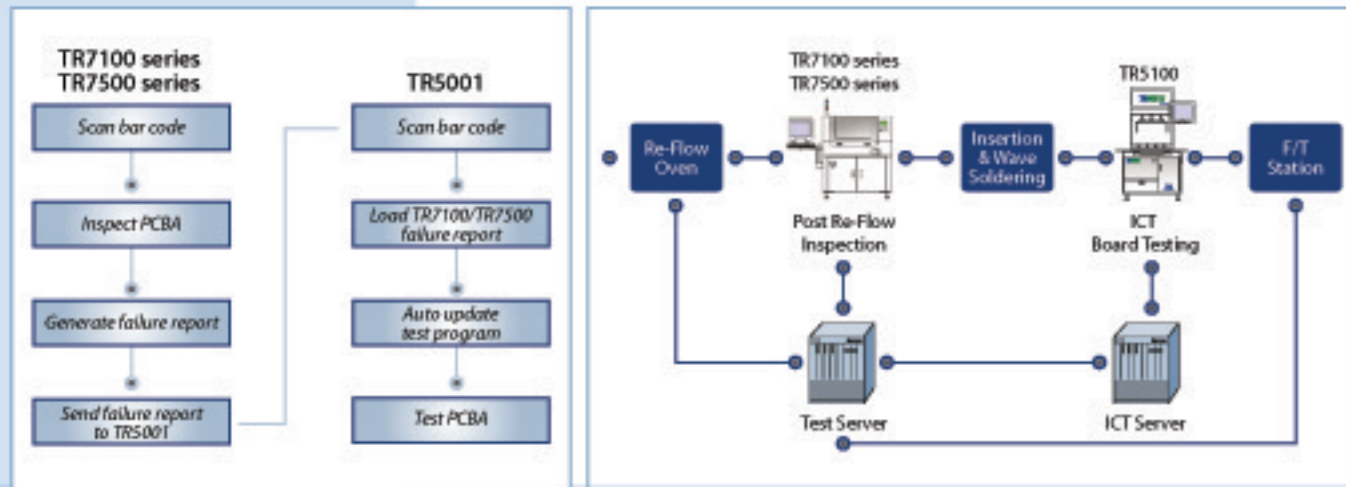
AUTO-LINK SOFTWARE FOR ICT AND AOI OPTIMIZATION



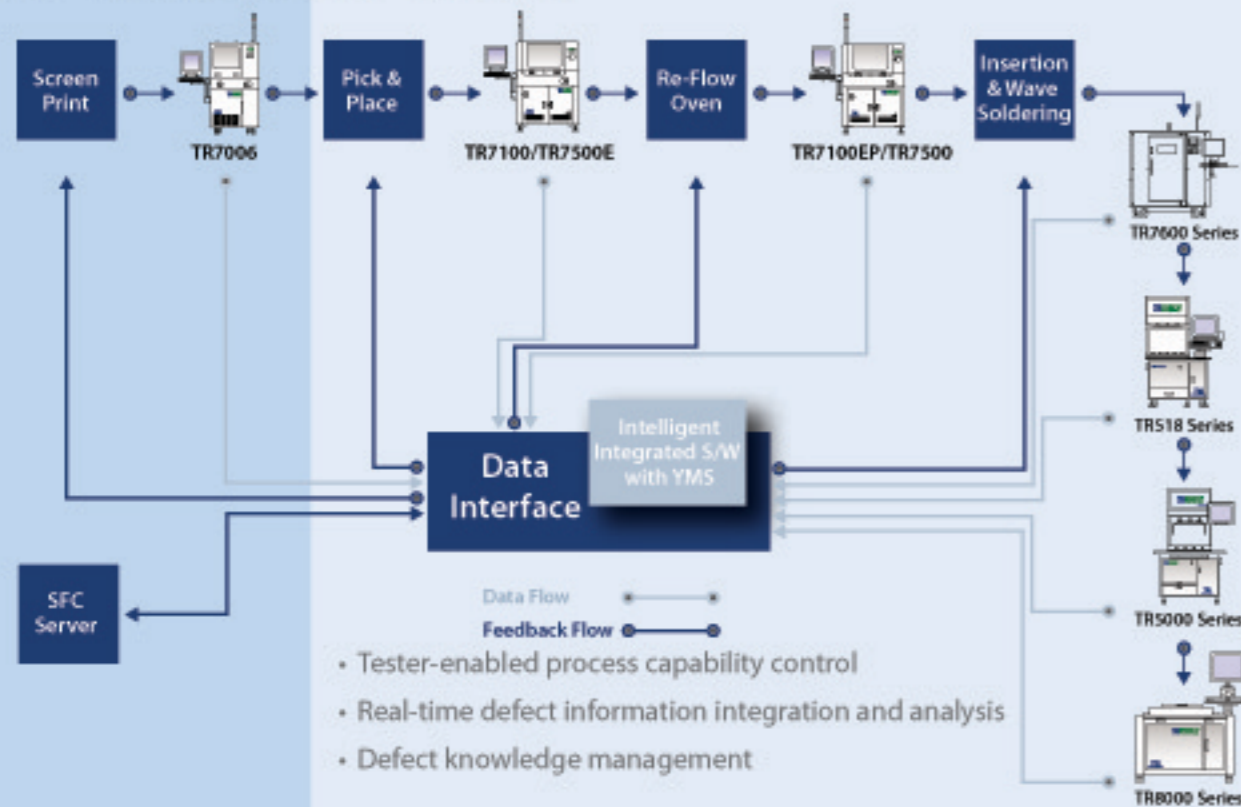
- Auto-link TR5001 ICT and TR7100/TR7500 Series AOI system to get the best strategy
- Optimized program development
- Test coverage analysis
- Automatic reconfirm if needed

SHOP FLOOR SYSTEM SUPPORT

- Supports Text File, Data Base, and Dll interfaces
- S/N and Operator ID check
- Multi-data exchange protocol



YIELD MANAGEMENT SYSTEM



- Tester-enabled process capability control
- Real-time defect information integration and analysis
- Defect knowledge management

GENERAL

Maximum Analog Test Points: 3200 or Maximum Digital Test Points: 1600  
 IBM® Compatible PC  
 Operation System: Microsoft® Windows 2000/XP  
 Power Requirement: 90-130V/180-240V Auto-Switch, 50/60Hz, 3KVA Max.  
 Air Requirement: Dry Air 6Kg/cm³, Air consumption: 4 Liter/cycle  
 Fixture Type: Press Type  
 Testable PCB Size: Standard: 420mm (W) x 300mm (D) x 100mm (H)  
 Option: 500mm (W) x 350mm (D) x 130mm (H). Large size PCB can be specially made

ANALOG HARDWARE

Measurement Switching Matrix: 6-wire measurement

Programmable Frequency: 100Hz, 1KHz, 10KHz, 100KHz, 1MHz  
 Programmable DC Voltage Source: 0 ~ ±12V, Resolution: 5.86mV  
 Programmable DC Current Source: 0 ~ ±200mA, Resolution: 0.2mA  
 Programmable AC Voltage Source: 0 ~ 7Vrms, Resolution: 5.86mV  
 Programmable High Voltage DC Source: 0 ~ 45V, 50mA

Component Measurement Capability

Resistance 1ohm ~ 40Mohm  
 Capacitance 1pF ~ 40mf  
 Inductance 1uH ~ 60H

Analog Measurement

AC Voltmeter: 0 ~ 100V  
 DC Voltmeter: 0 ~ ±100V, Resolution: 2.5mV ~ 50mV  
 DC Ampmeter: 1uA ~ 160mA, Resolution: 30nA ~ 30uA

OPTIONAL HARDWARE

Analog Test

TestJet Technology: Vectorless Open Circuit Detection  
 Arbitrary Waveform Generator (AWG): Frequency Range 0 ~ 100KHz, Resolution: 0.15Hz

Digital/Functional Test

Non-Multiplexing 1:1 Per Pin Architecture  
 Pin Drivers: Programmable Levels 0.5V to 4V  
 Pin Receivers: Programmable Levels -5V to 5V  
 Maximum Sink/Source Current 500mA  
 Output Impedance: < 1ohm  
 Pull-up/Pull-down Resistor 4.7K  
 DUT Power Supplies: 5V@3A, 3.3V@3A, 12V@3A, 18V@3A, -12V@3A, 24V@2A  
 Programmable DUT Power Supplies: 0V@20A, 15V@12A, 25V@8A, 36A@5A, 55V@3.5A, 75V@2.5A, 100V@2A  
 On-Board Programming of Flash & EEPROM Memories  
 MAC Address Programming: Supports MAC Address Programming with MAC address being supplied from server  
 Boundary Scan: includes B-Scan Chain Test, B-Scan Cluster Test & B-Scan Virtual Nails Test Facilities  
 Tree Test Facilities with BGA Test: Pattern Generator for Detection of Pin Opens for BGA/VLSI Chip  
 Support PXI, GPIB, RS-232 Standard Architecture for Functional Test

DIMENSIONS/WEIGHT

Width x Depth x Height/Weight: 1050mm x 850mm x 1660mm/300kgs

POWERFUL SOFTWARE ENVIRONMENT

Microsoft® Windows Operating System Software User Friendly Interface  
 Automatic Test Program Generator  
 Automatic Disable Generation of Surrounding Components  
 Automatic Test Generation with Auto-Learning of Open/shorts Using IC Clamping Diode and TestJet Technology  
 Auto Debug of Passive Components  
 Built-in Self-Diagnostic Function  
 Board View Displays Test Fail Devices and Pins Instantly

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T R 5 0 0 1 I C T



- FULL UPGRADE OPTIONS FROM MDA TO ICT AND FUNCTIONAL TEST
- COST-EFFECTIVE DIGITAL 1:1 DRIVER/RECEIVER PER PIN ARCHITECTURE DESIGN
- POWER BOUNDARY SCAN TEST SOLUTIONS
- ADD FUNCTIONAL TEST WITH PXI MODULES
- EASY-TO-USE ON-BOARD PROGRAMMING SOFTWARE



LEANSTREAM™ LLC

Phone: 408-894-9400.  
 Fax: 408-954-9989.  
 Email: info@lean-stream.com



LEANSTREAM™ LLC  
 innovation

## ANALOG TEST

### HIGH-PERFORMANCE MANUFACTURING DEFECTS ANALYZERS (MDA)



#### TESTJET TECHNOLOGY

To find open connections to surface-mount technology (SMT) devices such as ICs and connectors.

#### INTEL® SOCKET TEST TECHNOLOGY

A superior test method that can replace Intel CPU B-Scan and TestJet with increased coverage.

- Test Coverage Comparison
- CPU using B-SCAN & TestJet  $\approx$  37%
- Socket Test Technology  $\approx$  98.6% (Measures power and ground connections with custom test socket)

#### CAPACITOR POLARITY TEST

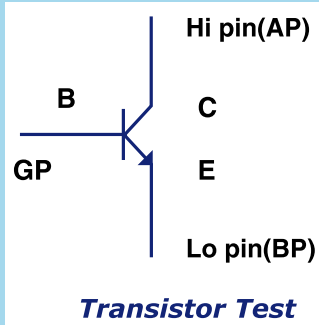
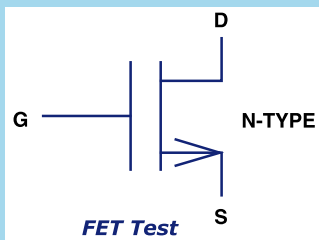
- Leakage Current Measurement
- TestJet Detection

#### TRANSISTOR/DIODE MEASUREMENT

- Diode
- Zener Diode Transistor: PNP, NPN
- FET/SCR/TRIAC
- Photo Coupler

#### RCL MEASUREMENT

- 6-Wire Measurement
- Auto-Guarding Feature
- AC Phase Measurement
- High-Speed Test



## DIGITAL TEST

### FULL DIGITAL IN-CIRCUIT TEST (ICT)

#### USER-FRIENDLY INTERFACE

TR5001 provides a simple to understand and flexible interface.

- Color syntax program editor
- C-like test language
- Editable waveform display tool
- Integrated development environment

#### EASY-TO-USE ON-BOARD PROGRAMMING SOFTWARE

Modularized memory algorithms provide convenient On-Board Programming solutions.

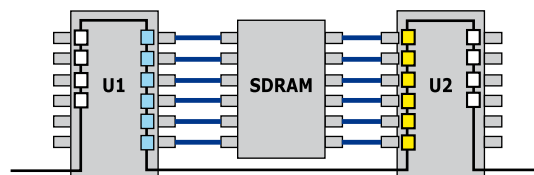
- Flash Programming
- Serial Device Programming

#### POWERFUL BOUNDARY-SCAN CLUSTER TEST CAPABILITY

Auto-Generation of test program and reporting through Boundary-Scan Test Program Generator (BSTG) for different kinds of test categories, such as individual boundary-scan device tests, boundary-scan devices chain test, and virtual nails test for RAM, ROM, TTL, TREE devices, and IEEE1149.6 Test.

#### THE MOST COST-EFFECTIVE TEST STRATEGY

- Non-Multiplexing Pin Design, Driver/Receiver to Pin Ratio 1:1.
- Optimized Nail Placement with 1:1 Ratio Flexibility
- ECNs do not require moving existing wires in your fixture
- 1:1 Driver/Receiver per pin provide for the fastest test program development and debugging



Boundary-Scan Virtual Test

## FUNCTIONAL TEST

### BUILT-IN PXI MODULE SOLUTION FOR FUNCTIONAL TEST

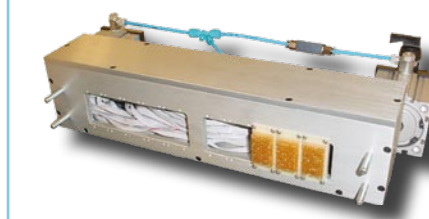
#### INTEGRATED IN-CIRCUIT AND FUNCTIONAL TEST IN ONE SYSTEM

Lowering Overall Test System Cost.

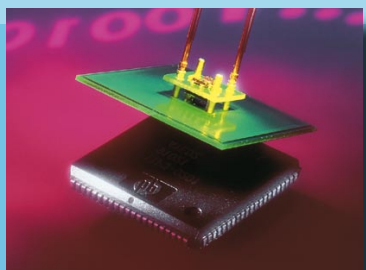
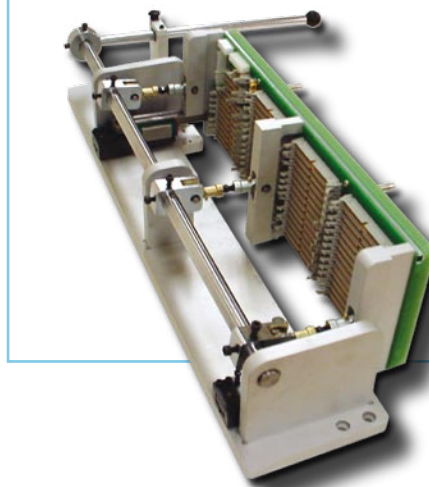
- Auto-integrate PXI software and hardware
- PXI hardware modules
- Supports RS232 interface and bus
- Wide selection of PXI or GPIB hardware options
- Share PC, fixture, and power supplies for all test strategies
- New 2-Stage press design for ICT & Functional Test

## OPTIONS

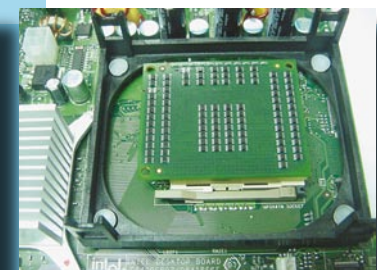
#### In Line Fixture Interface



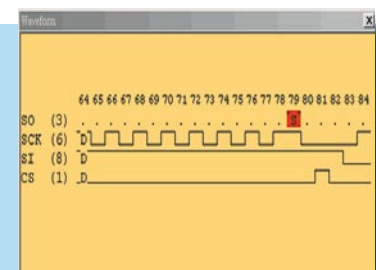
#### Quick Disconnect Interface



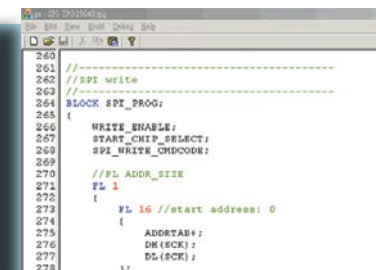
TestJet Technology



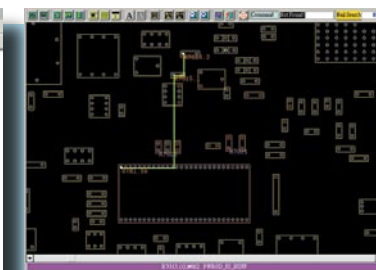
Intel Socket Test Technology



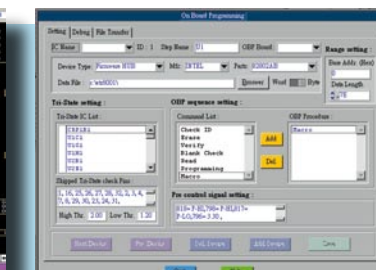
Waveform display



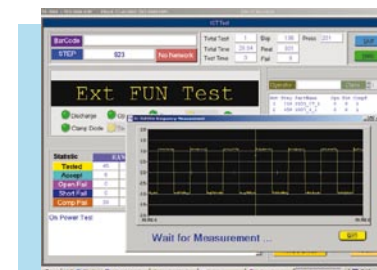
Color syntax program editor



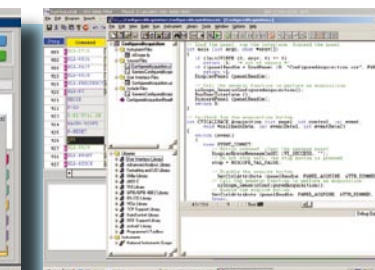
Board view with trace display capacity



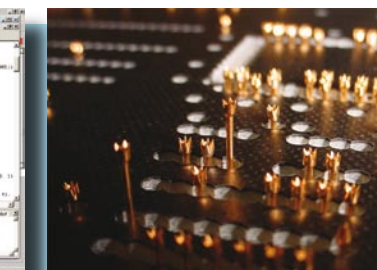
Flash programming



Free running functional test result



Supports NI-CVI functional programming



Longest probe for 2-stage fixture



2-stage press design